

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): ERAN DVIR, MOSHE FINAROV, ELI HAIMOVICH,
BENJAMIN SHULMAN
Assignee: Nova Measuring Instruments, Ltd.
Title: "APPARATUS FOR OPTICAL INSPECTION OF WAFERS
DURING POLISHING"

Serial No.: 08/497,382 Filing Date: June 29, 1995

Examiner: E. Morgan Art Unit: 3203

Attorney Docket No.: M-3417-US

San Jose, California
December 30, 1996

COMMISSIONER OF PATENTS AND TRADEMARKS
Washington, D. C. 20231

RESPONSE TO RESTRICTION REQUIREMENT

Sir:

REMARKS

This paper is in response to the paper dated October 2,
1996. In that paper the Examiner issued a restriction to one
of the following inventions under 35 U.S.C. §121:

- I. Claims 1-10, 13-16, drawn to measuring the
thickness of a wafer, classified in class
451, subclass 6.
- II. Claims 11, 12, drawn to a method of placing
a wafer in water, classified in class 437,
subclass 984.

Applicants hereby elect Group I, Claims 1-10, 13-16 for
examination. If the Examiner has any questions concerning this
paper, the Examiner is respectfully requested to telephone
Applicants' attorney at the number given below.

Respectfully submitted,

Forrest E. Gunnison
Reg. No. 25,825

Forrest E. Gunnison
Attorney for Applicant(s)
Reg. No. 32,899
(408) 453-9200

I hereby certify that this correspondence is being deposited with the
United States Postal Service as first class mail in an envelope
addressed to: Commissioner of Patents and Trademarks, Washington,
D.C., 20231, on December 30, 1996.

Dec 30, 1996
Date of Signature

Forrest E. Gunnison
Attorney for Applicant(s)

LAW OFFICES OF
ERNEST, MORSELL,
MACPHERSON, FRANKELIN
& PIERCE

25 MISTRO DRIVE
SUITE 300
SAN JOSE, CA 95130
(408) 433-9000
FAX (408) 433-7979